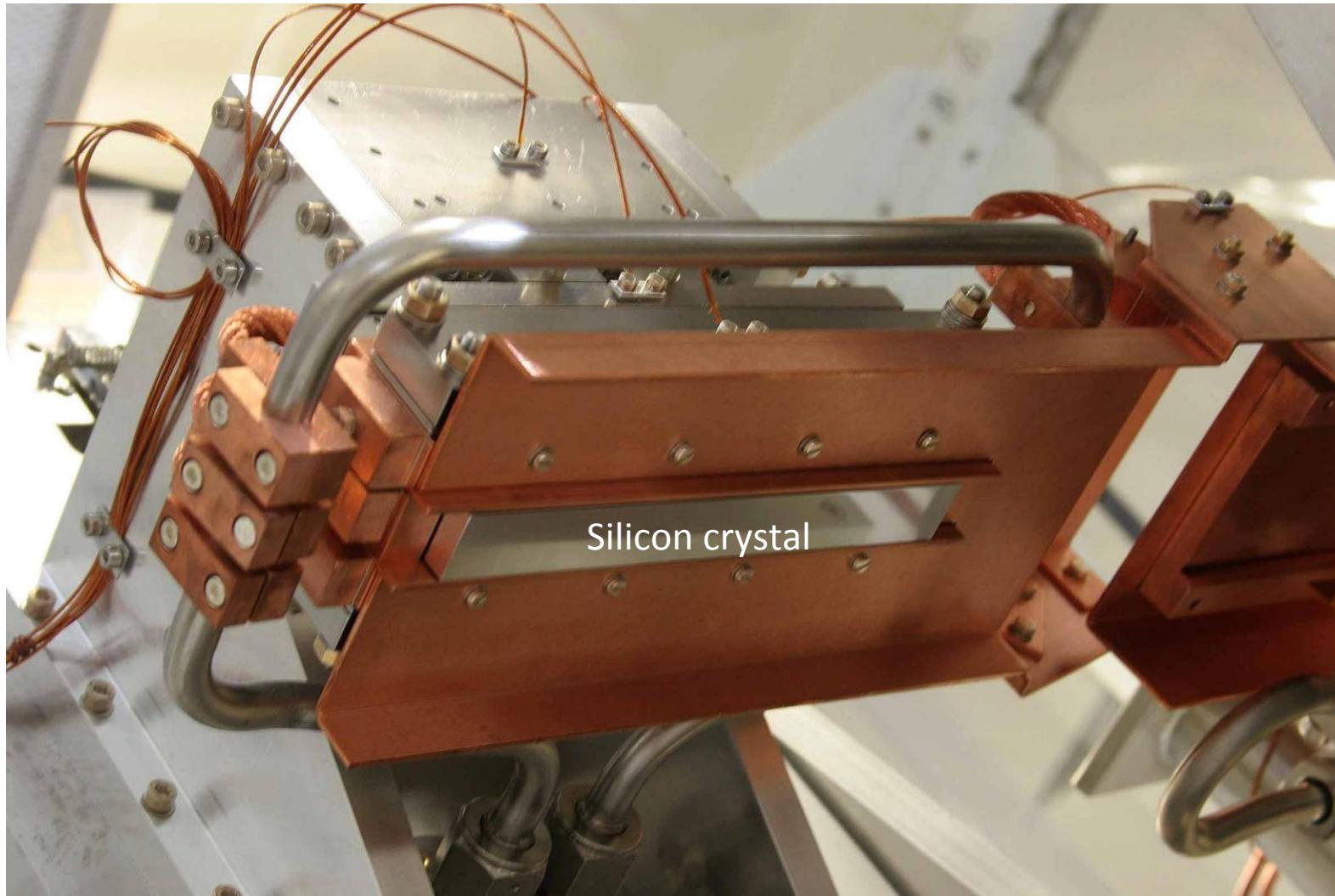


+ Cryogenic cooling of monochromator crystal

LN_2 cooling (Diamond)





Omitted topics

Electron analyzer

Crystal/multilayer analyzer

Ultra-fast detectors

Timing instruments



Detectors

Ionization chamber, solid state detectors
(Silicon, Germanium...)

+ Detectors used in XAS experiments

Beam monitor

F detector

A. Ionization chamber (standard beam monitor in hard x-ray region)

a. Ambient gas pressure type

Control of absorbance: Mixing gas (N₂-He, N₂-Ar)

b. Pressurized gas type

Control of absorbance: Low vacuum, high vacuum

c. Lytle detector

Fluorescence detection where energy resolution is not required

B. Solid state detectors (SSD) Energy resolution: 135-220 eV @5.9 keV

Silicon (Li) Pure Ge Upto 100 pixels; Oyanagi, NIM A513, 340 (2003).

C. Silicon drift diode (SDD) Energy resolution: 130 eV @5.9 keV

Upto five elements (?)

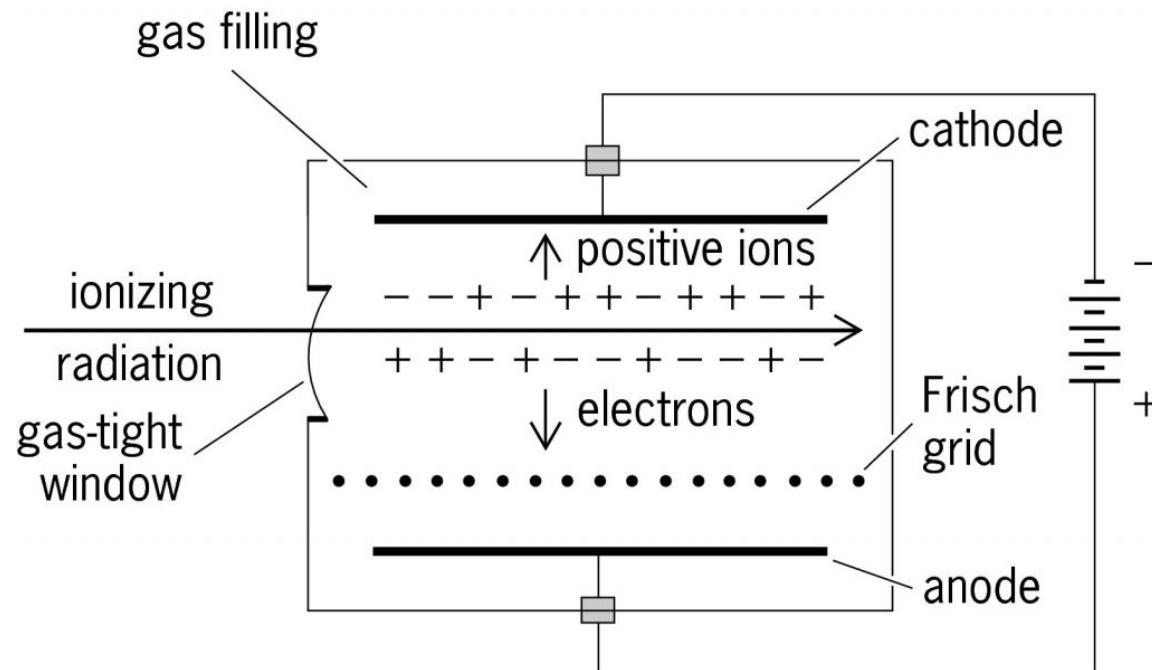
D. Si APD Fast response detector Energy resolution ≈26%

Kishimoto, RSI 63, 824 (1992)

E. Scintillation detector, NaI, plastic Energy resolution (NaI) ≈46%

F. Multilayer monochromator

+ Ionization chamber -Principle

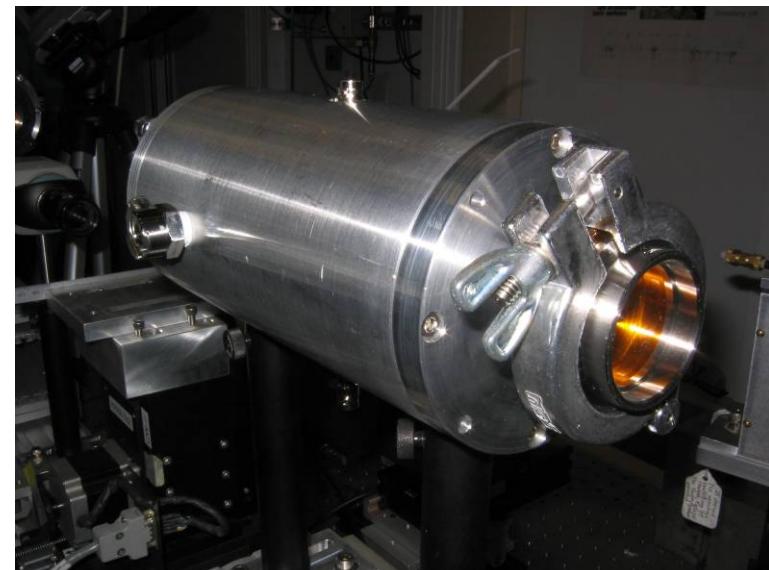


Note: frequent spike noise
comes from a discharge
Low voltage is recommended

Two types of ionization chamber

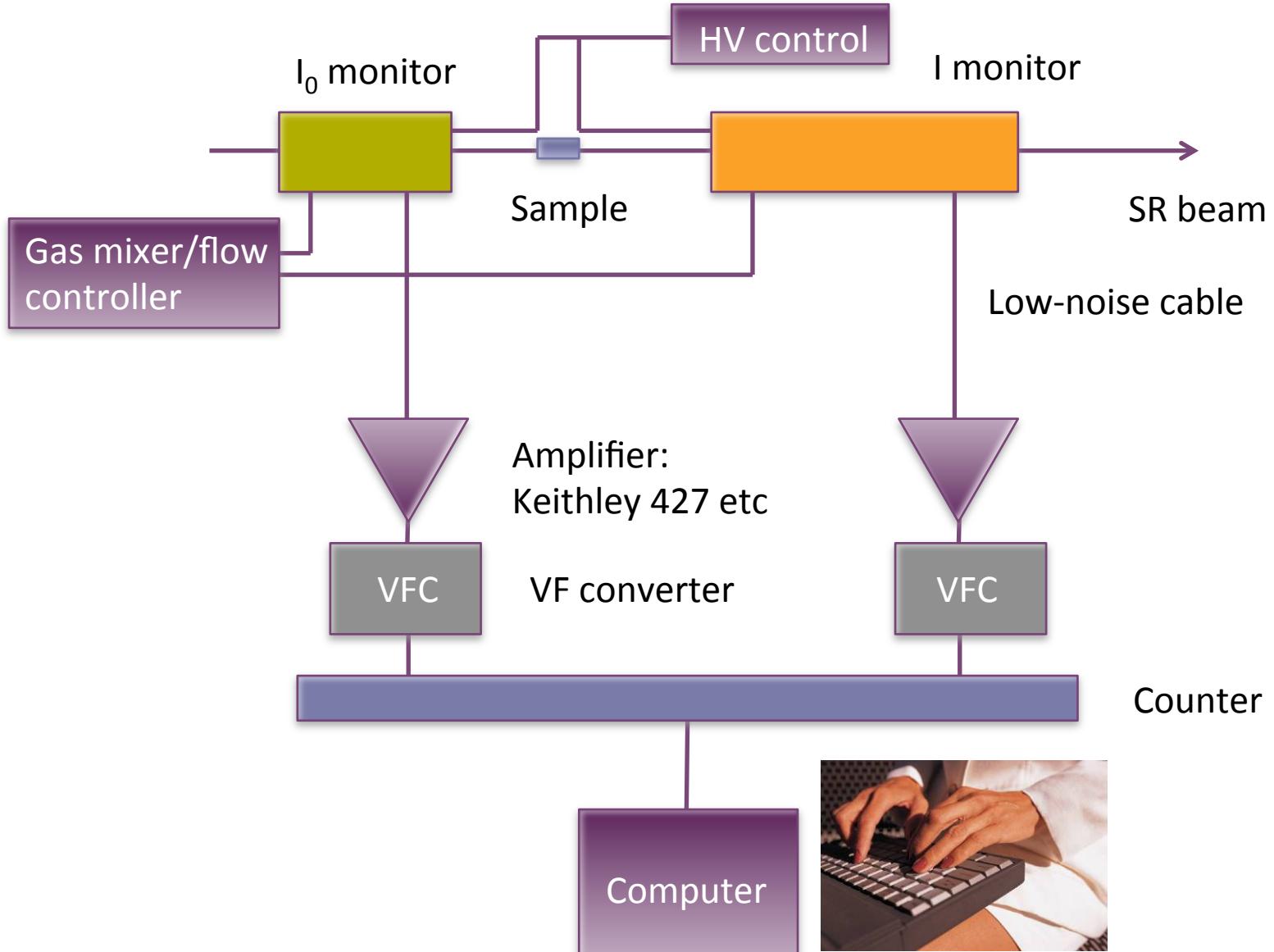


@PF



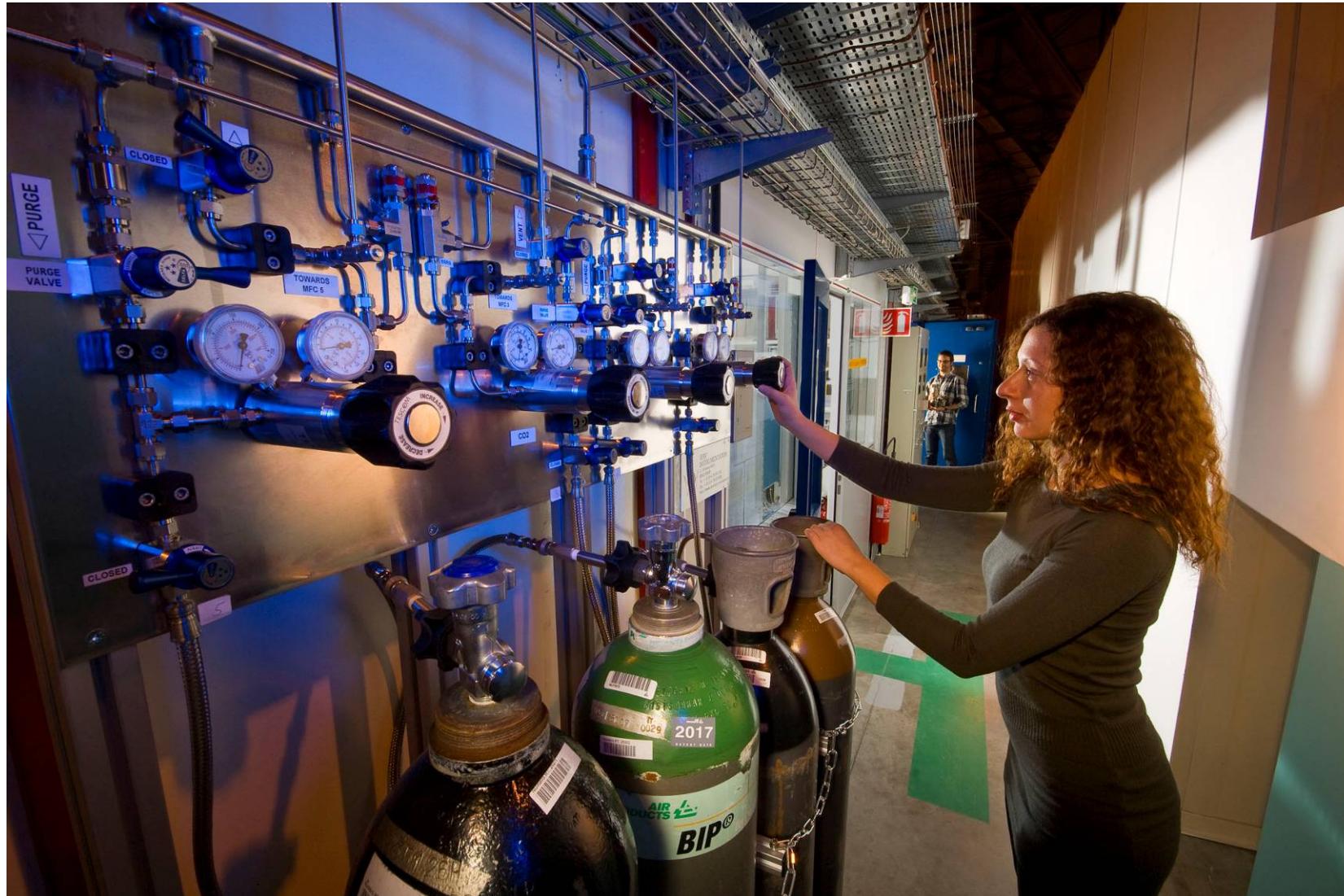
@CLS

+ Conventional setup (Analog amplifier)

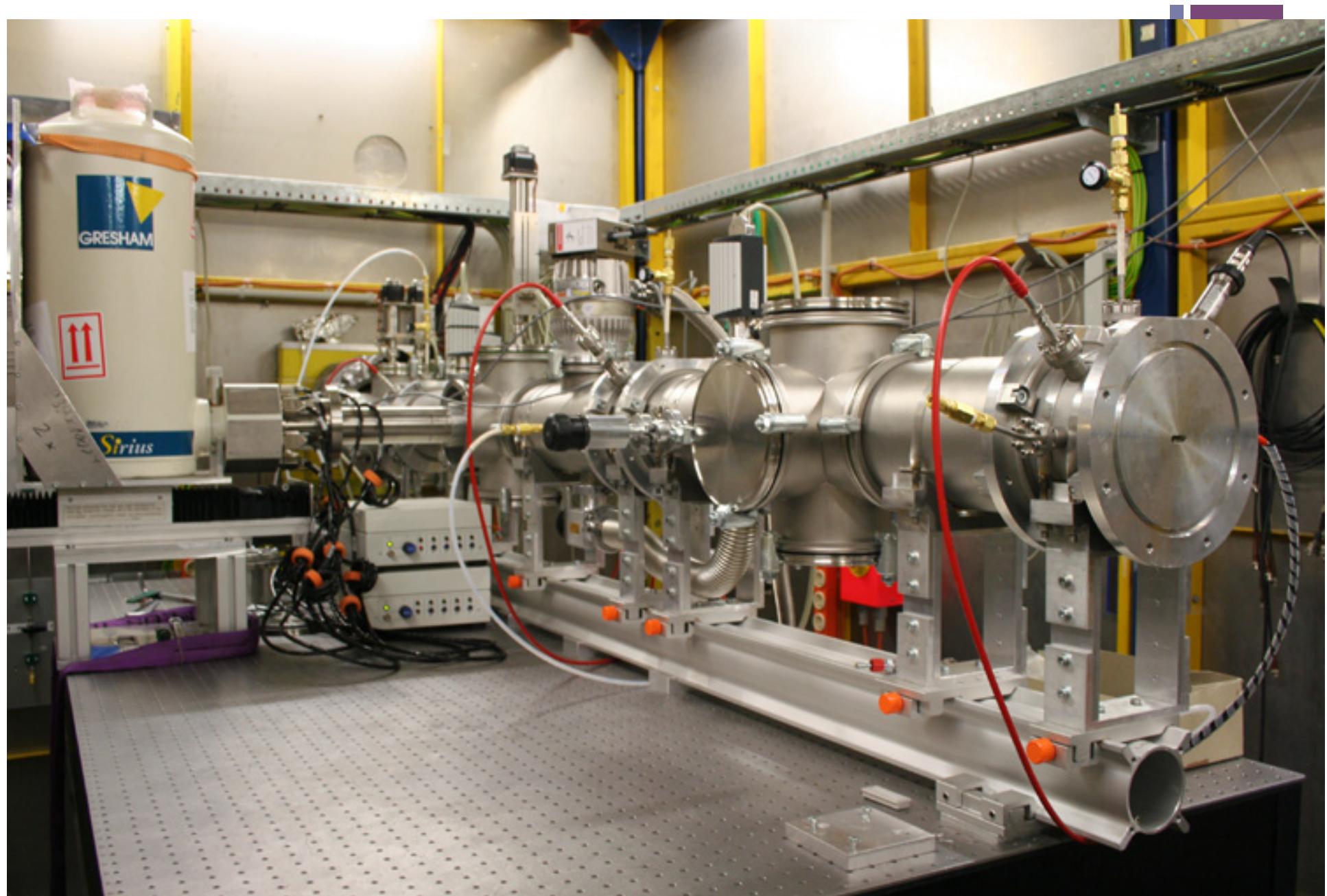


+ Ionization gas control

Controlled gas flow makes a stable signal output



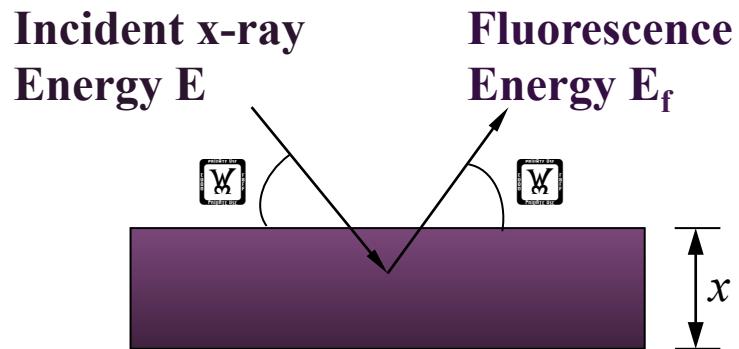
@ESRF



Pressurized ionization chamber setup at APS

+ Fluorescence intensity estimation

For x-rays incident on a slab of sample with thickness of x :



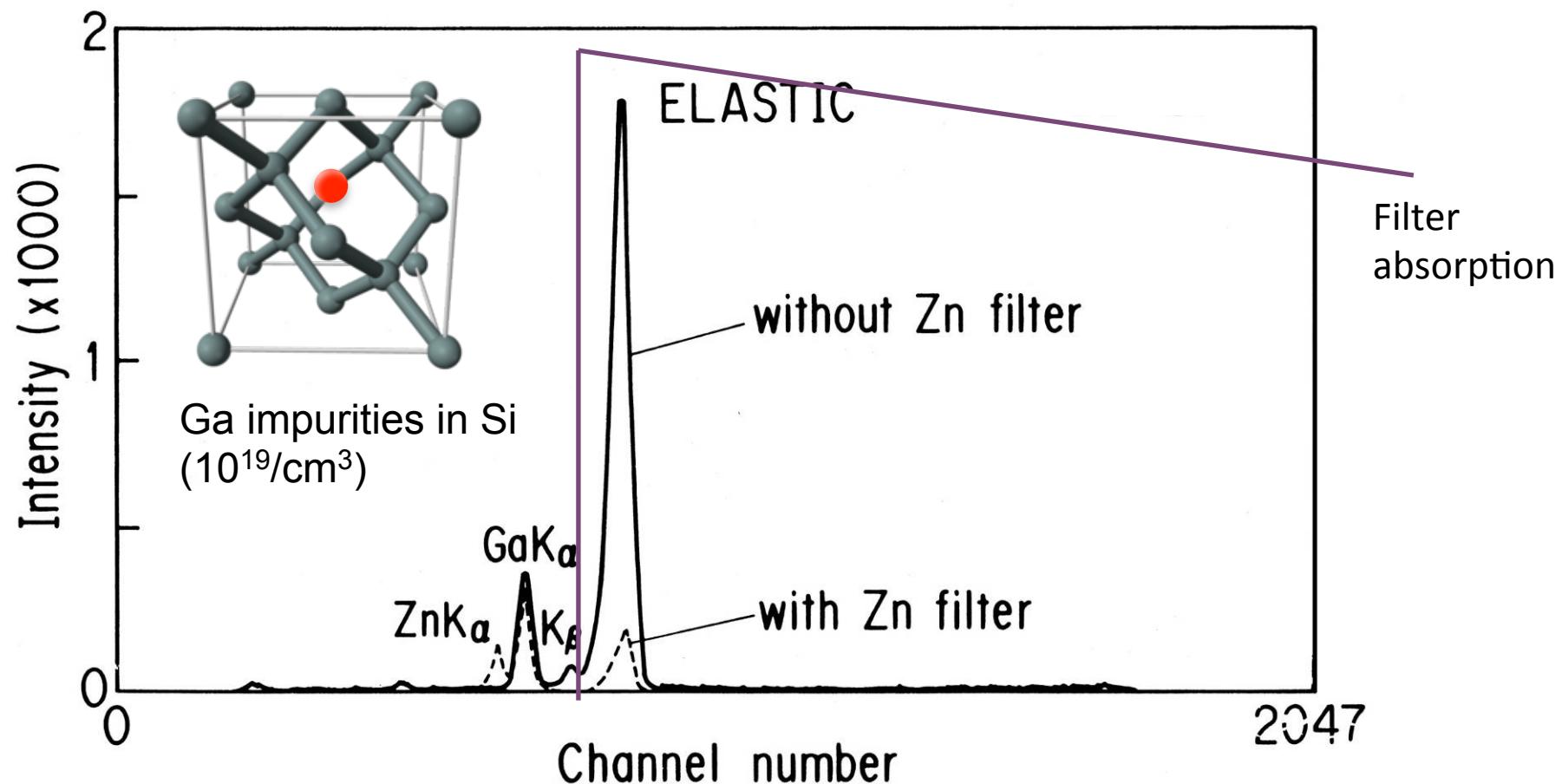
The fluorescence intensity $I_f(E)$ accepted by a detector with a solid angle of $\Omega/4\pi$ is:

$$I_f(E) = I_0 \left(\frac{\Omega}{4\pi} \right) \epsilon \mu_{Se}(E) / \sin \Theta \frac{1 - \exp[-(\mu(E) / \sin \Theta + \mu(E_f) / \sin \Phi)x]}{\mu(E) / \sin \Theta + \mu(E_f) / \sin \Phi} \quad (1)$$

$I_f(E) \approx I_0 \cdot 8.8 \cdot 10^{-4} \cdot 0.012 \cdot 1 \cdot 10^{-5} I_0$, lower than I_0 by 5 orders.

+ Fluorescence detection technique (Z-1 filter)

With a sacrifice of $\frac{1}{2}$ intensity reduction, one order of magnitude
Of elastic x-ray background is removed by a fluorescence filter



+ Lytle detector

Basically ionization chamber

Soller slit assembly to remove scattering and fluorescence background

www.exafesco.com/

@SagaLS



@APS

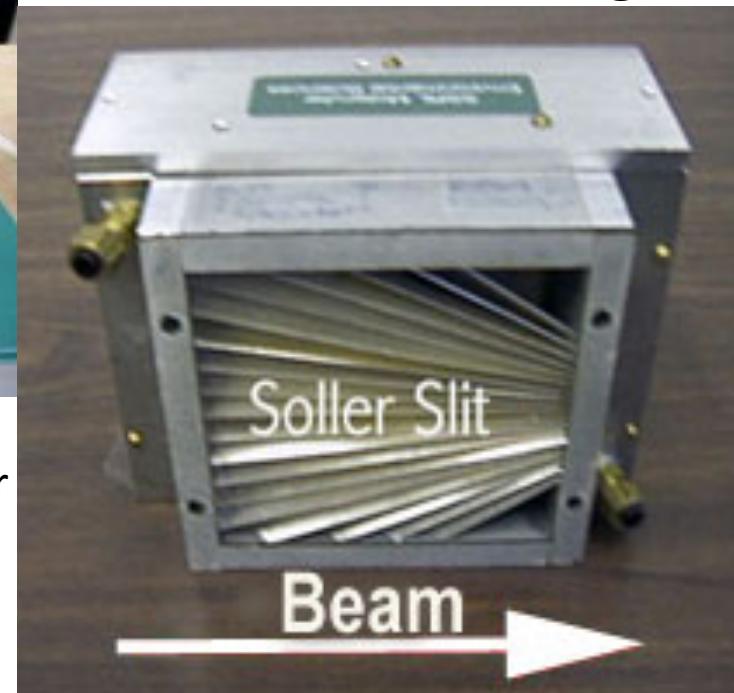


Figure 2. Soller Slit Position

Note: easy-to-use and low-cost fluorescence detector

Note: never use in multi fluorescence signal sample

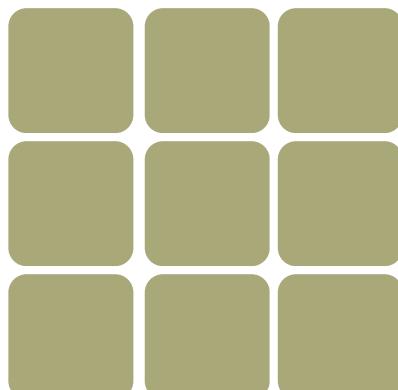
+ NaI array

For simple case, i.e., a single fluorescence line, energy resolving power becomes unimportant

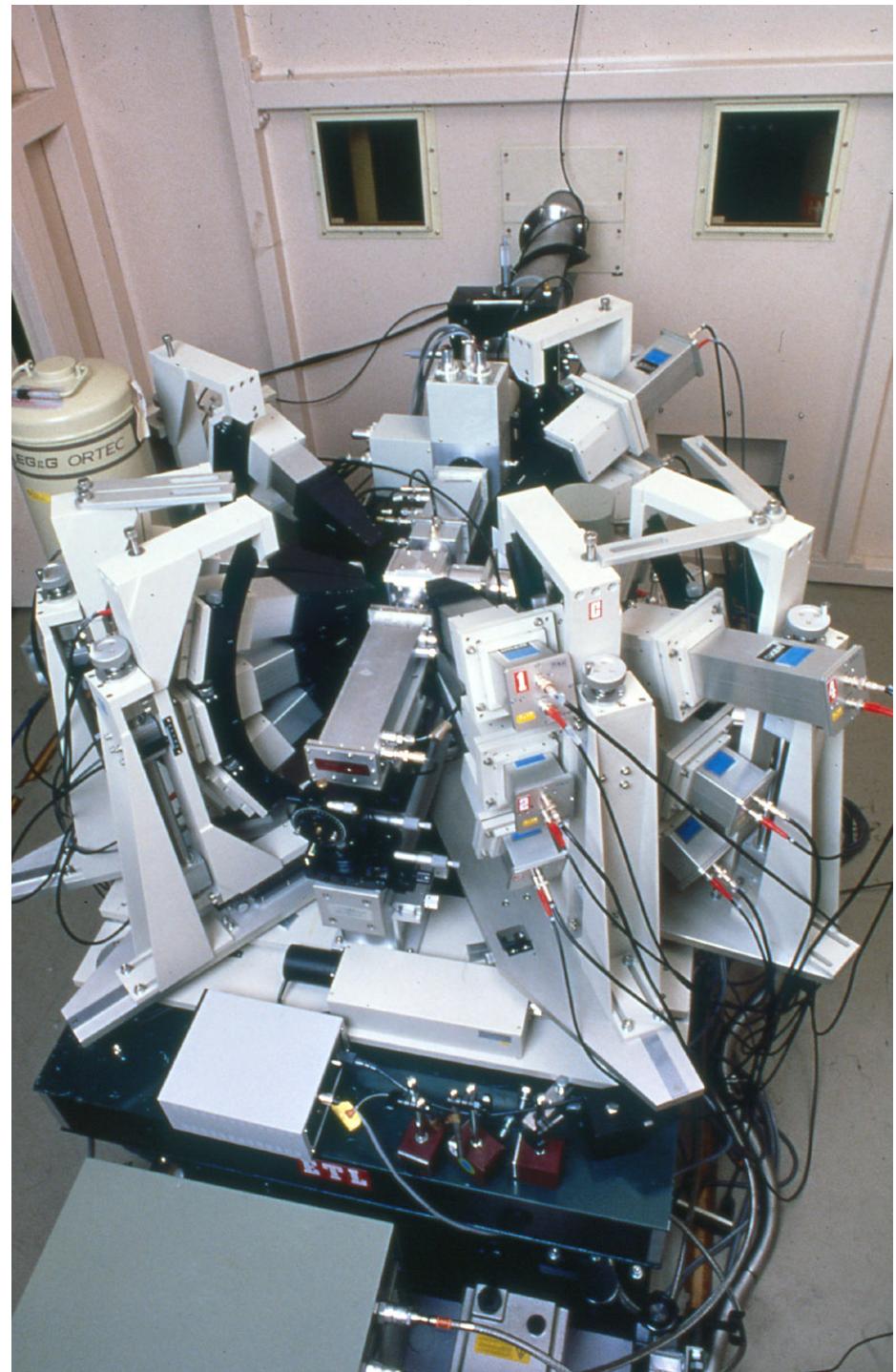
Lytle detector
Si APD ($DE \approx 26\%$)
NaI array (40-50%)

High coverage of solid angle but ...
Low energy resolution

18% of 4p
 $DE = 41\% E$

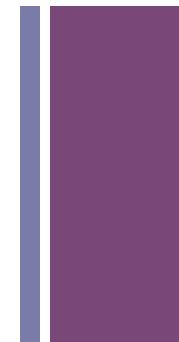


Focused beamline with a NaI array
BL4C, 10C@PF



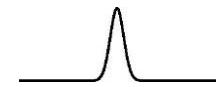
+ SSD (Solid State Detector)

-a CMOS device for x-rays



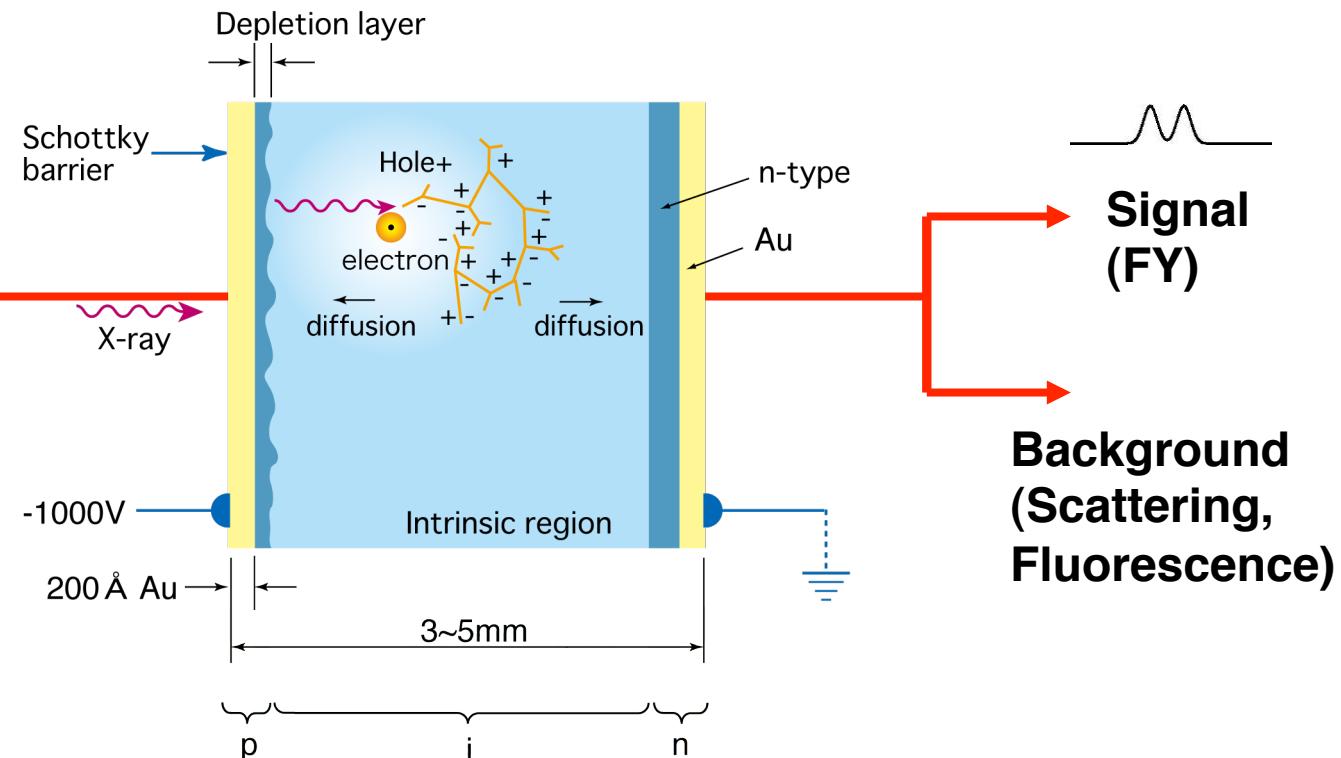
**Each pixel acts as
an independent
SSD device**

Signal (fluorescence) must be
separated from elastic scattering
And other backgrounds



Technical Problem

SiO_2 forms strong
passivation layer
but GeO_2 is not
strong
Leakage current is
A noise source



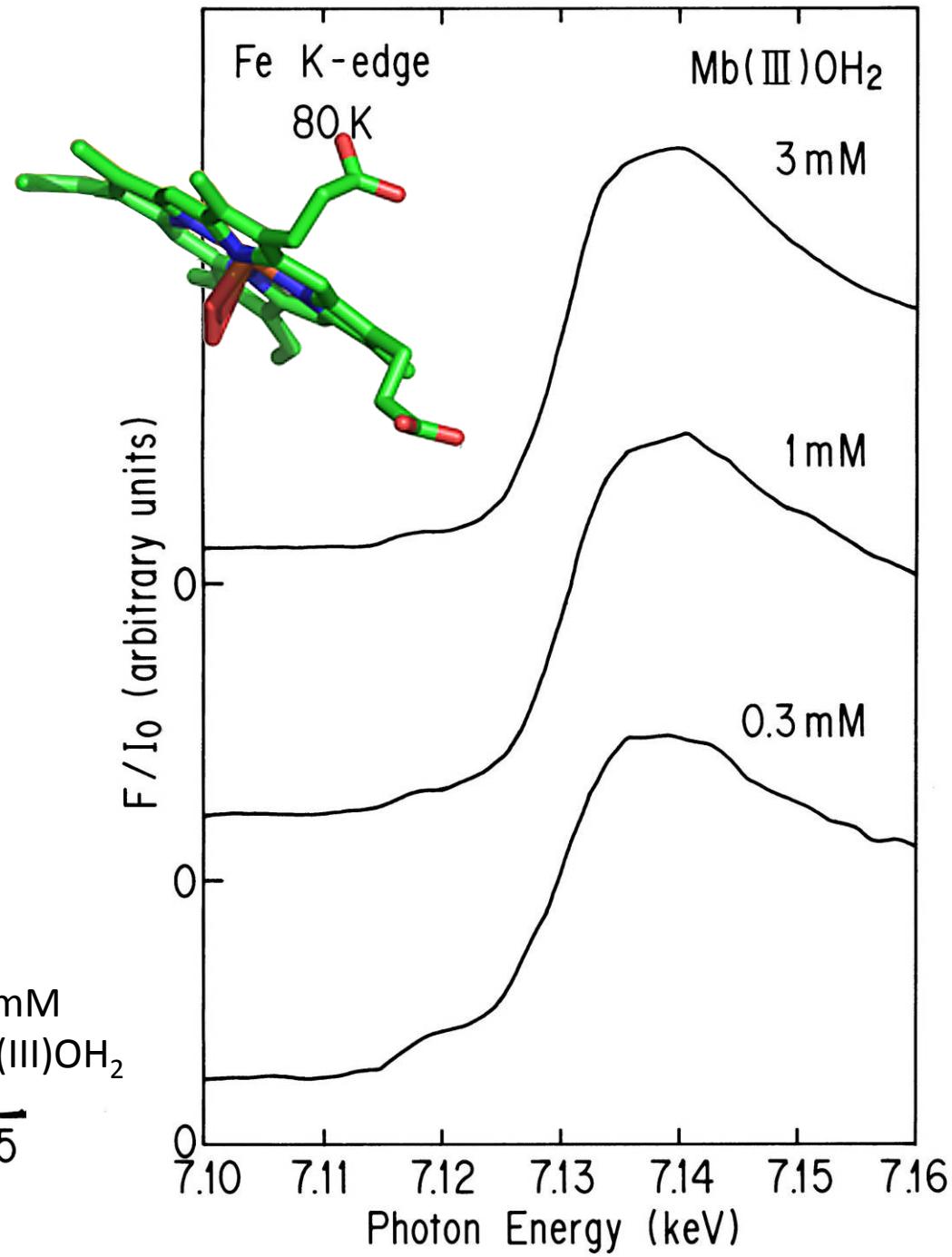
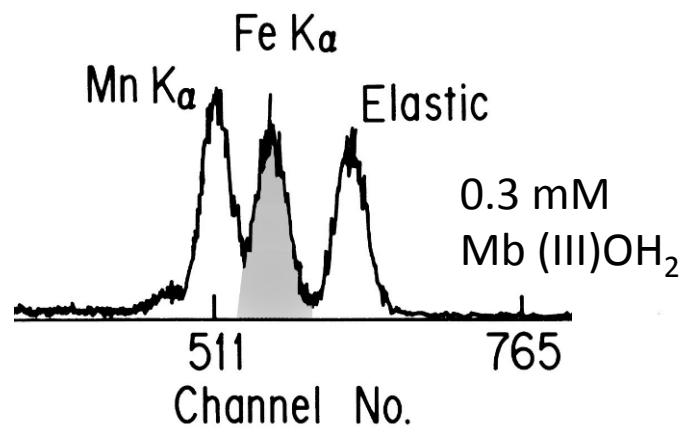
+ Fe K-XANES

Sample: $\text{Mb(III)}\text{OH}_2$

Signal: Fe fluorescence

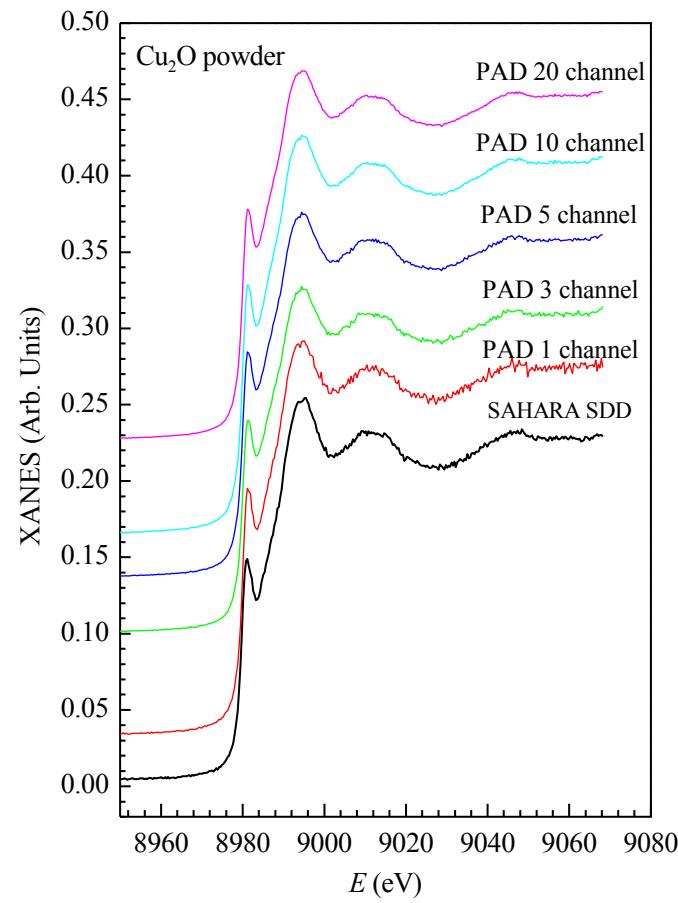
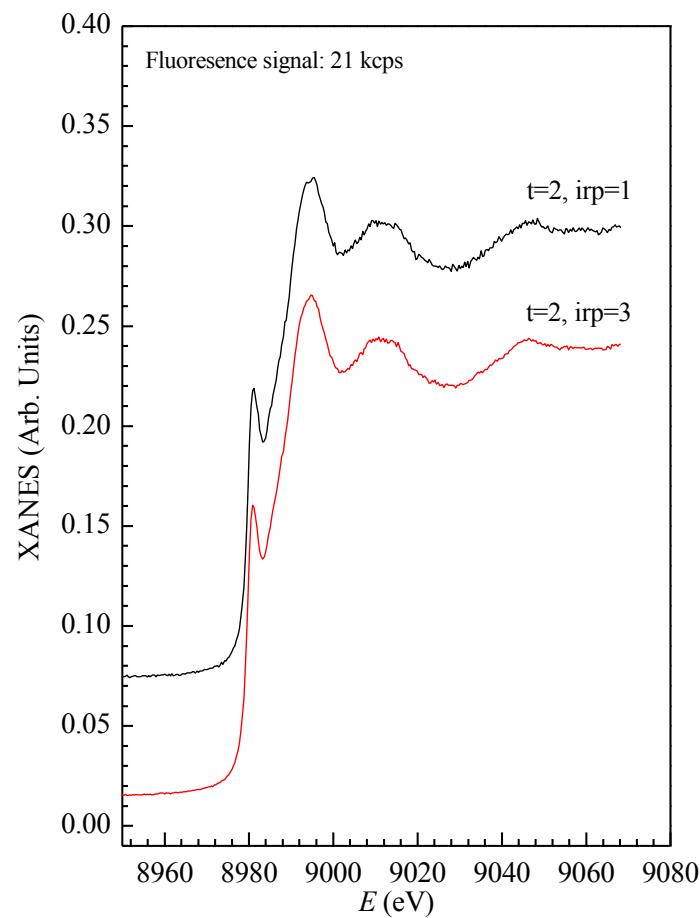
Background: Filter
fluorescence plus
elastic scattering

Statistics: Proportional
to the square root of the
accumulated number of
photons



+ Statistics in fluorescence XAFS

- a. Repeating scans
- b. Segmented detection



+ Evolution of pixel array detector

1st Generation

5 mm x 5 mm
100 pixels

215 eV@5.9keV

No. 1 Spring-8 (Oyanagi)

09	19	29	39	49	59	69	79	89	99
08	18	28	38	48	58	68	78	88	98
07	17	27	37	47	57	67	77	87	97
06	16	26	36	46	56	66	76	86	96
05	15	25	35	45	55	65	75	85	95
04	14	24	34	44	54	64	74	84	94
03	13	23	33	43	53	63	73	83	93
02	12	22	32	42	52	62	72	82	92
01	11	21	31	41	51	61	71	81	91
00	10	20	30	40	50	60	70	80	90

No. 2 Photon Factory (Oyanagi)

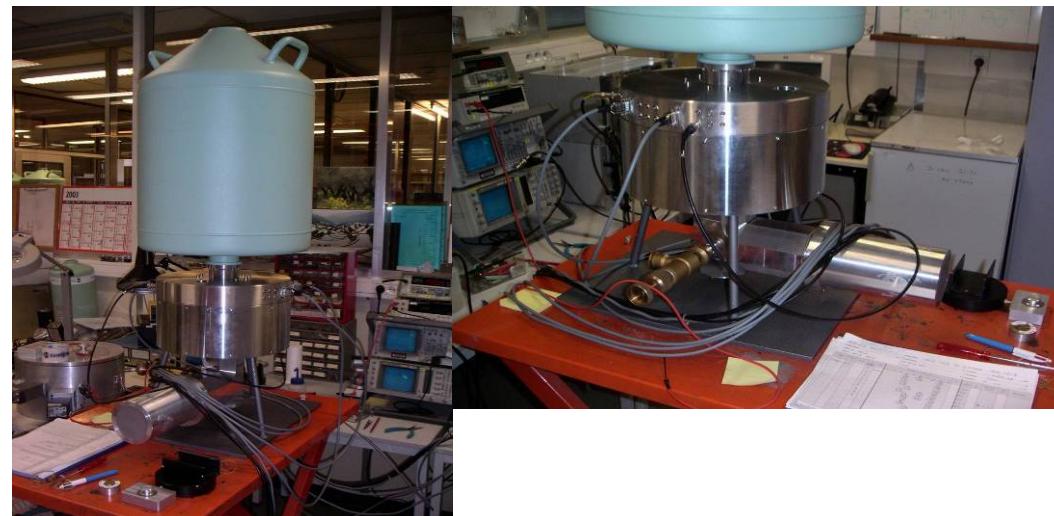
09	19	29	39	49	59	69	79	89	99
08	18	28	38	48	58	68	78	88	98
07	17	27	37	47	57	67	77	87	97
06	16	26	36	46	56	66	76	86	96
05	15	25	35	45	55	65	75	85	95
04	14	24	34	44	54	64	74	84	94
03	13	23	33	43	53	63	73	83	93
02	12	22	32	42	52	62	72	82	92
01	11	21	31	41	51	61	71	81	91
00	10	20	30	40	50	60	70	80	90

2nd Generation

5 mm x 5 mm
36 pixels

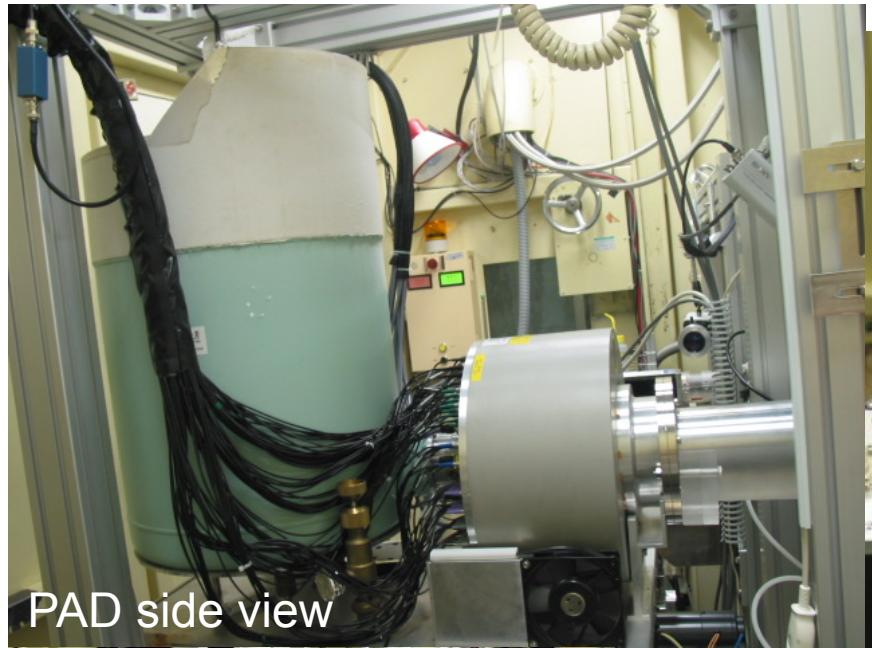
165 eV@5.9keV

No. 3 Australian Beamline at PF (Foran et al.)



3rd Generation

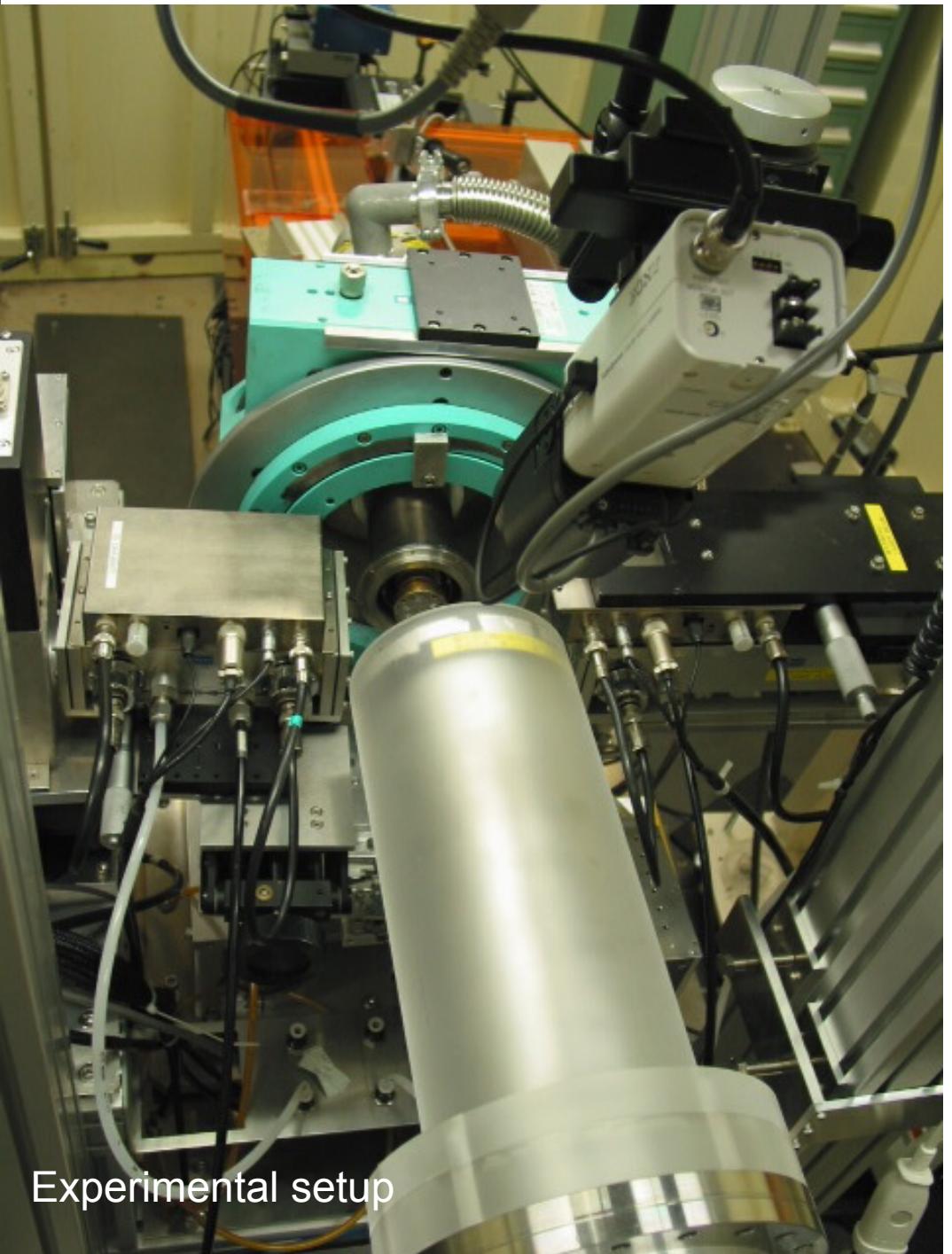
Now in operation in Australian light source



PAD side view



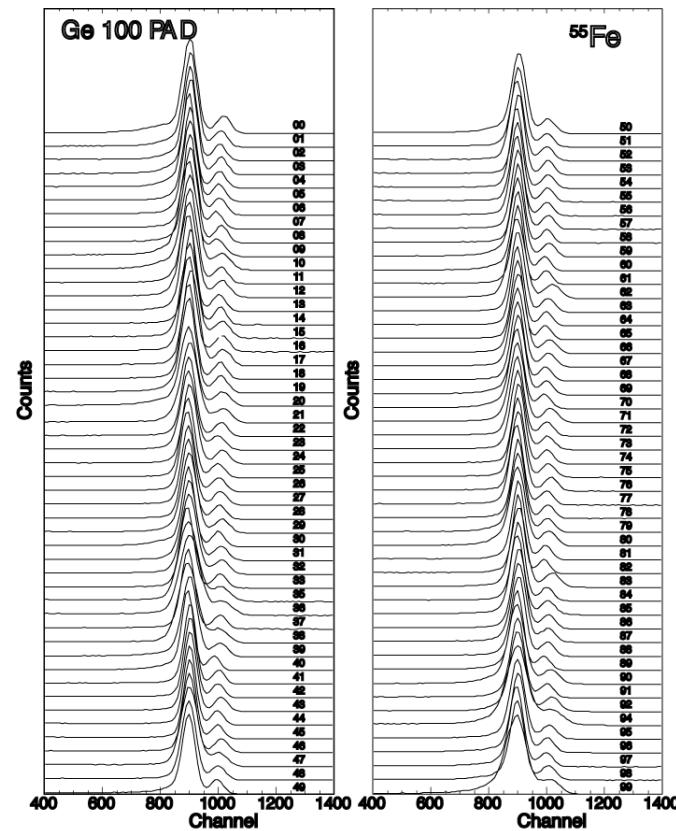
PAD front view



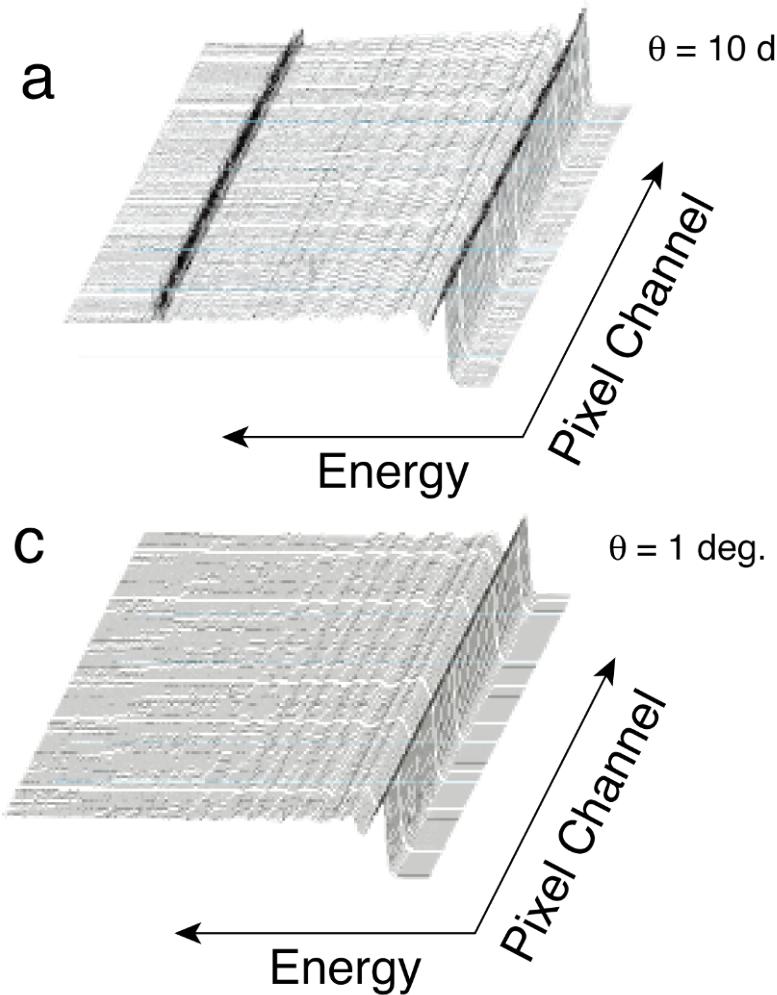
Experimental setup

+ Advantage of PAD

Real time fluorescence monitoring
over a large segmented solid angle

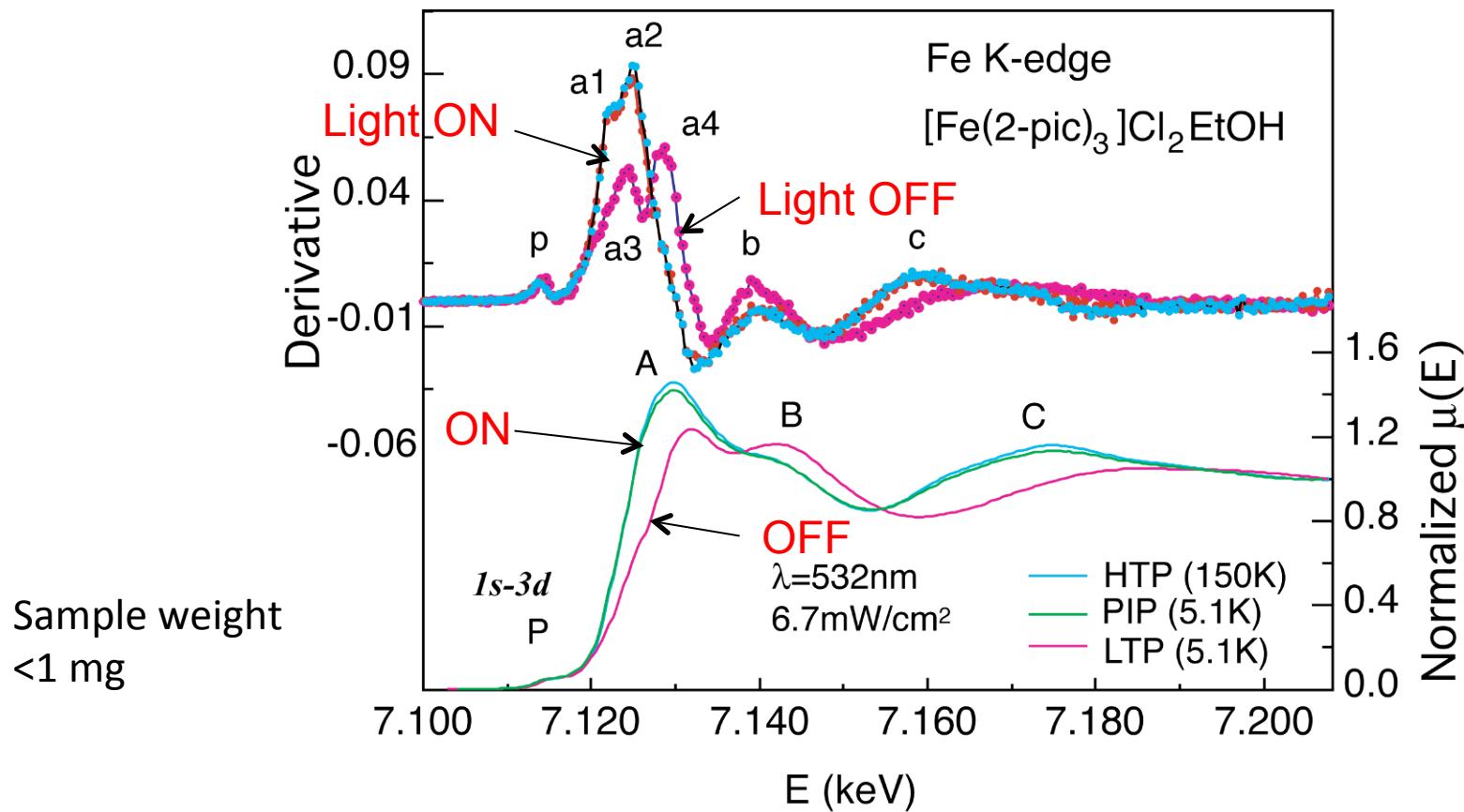


MCA output for 100 pixels



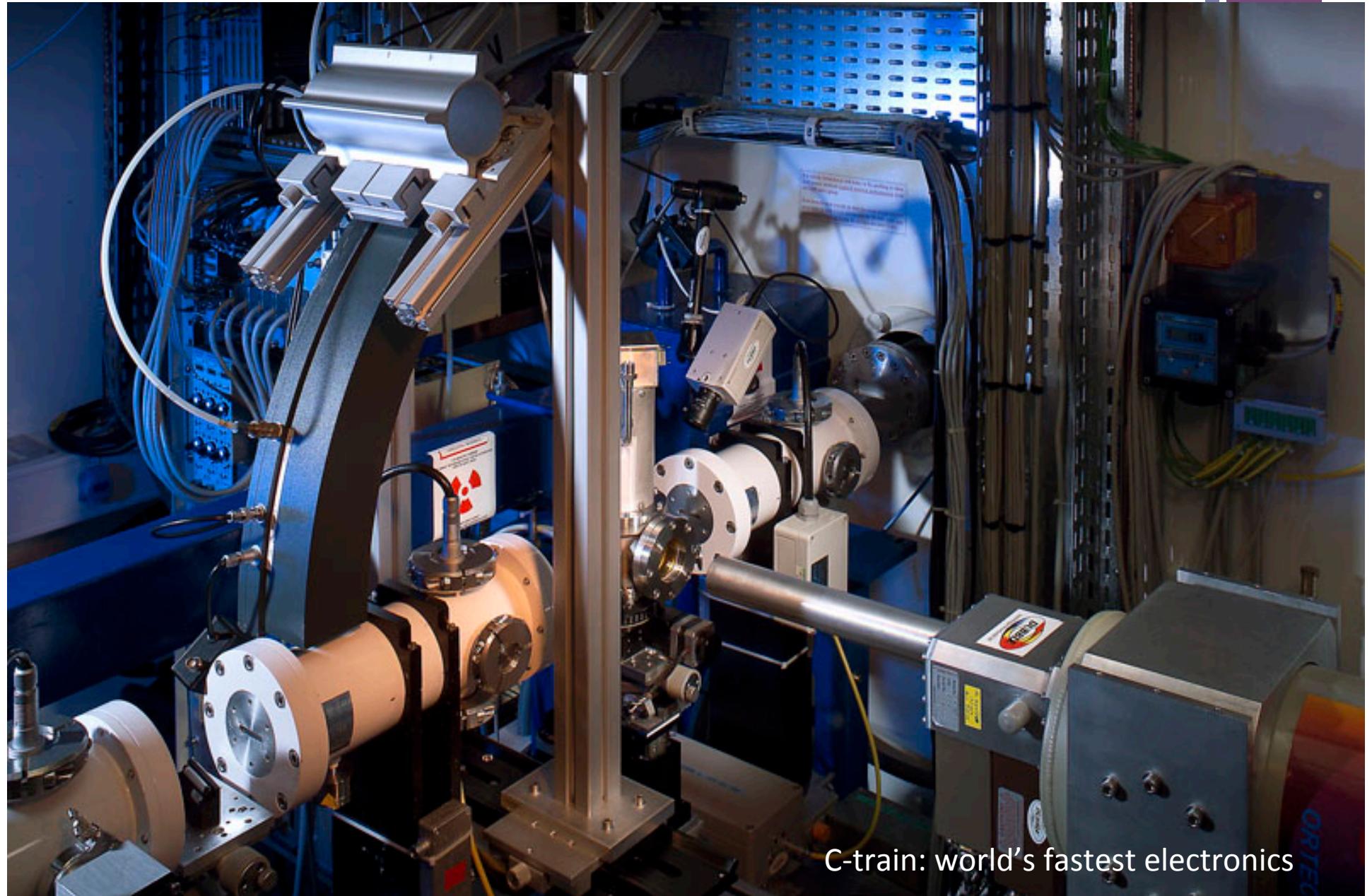
Glitches (scattering, standing wave, other elements)
are completely removed.

+ Photo-induced spin crossover
–fluorescence detection by Ge PAD



Laser illumination changes Fe spin state from S=0 to S=2
No symmetry breaking!

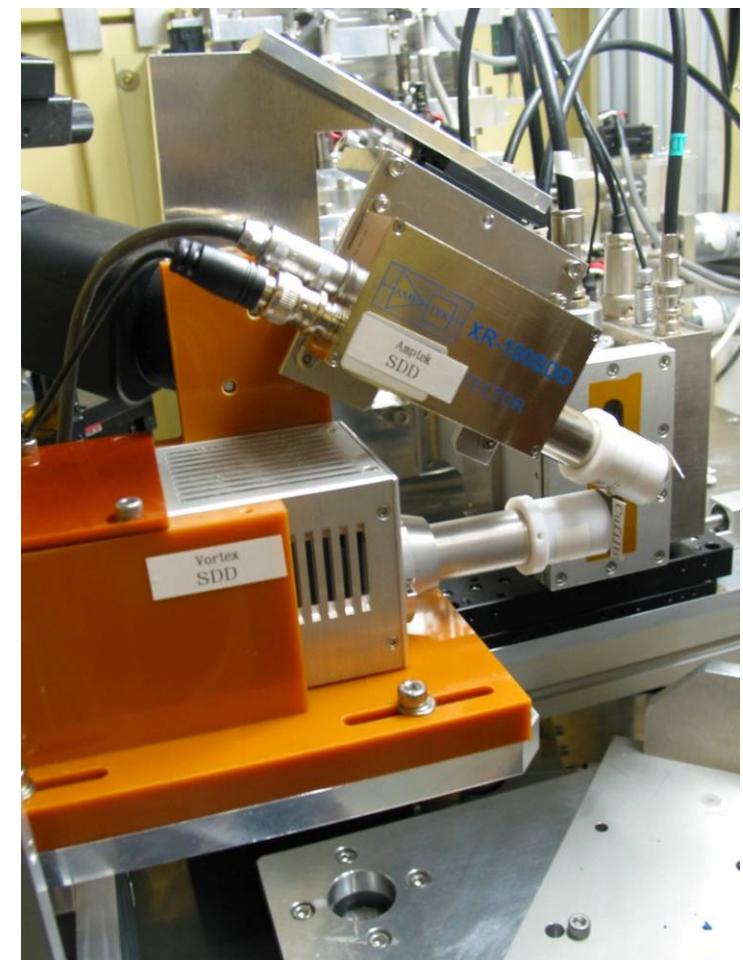
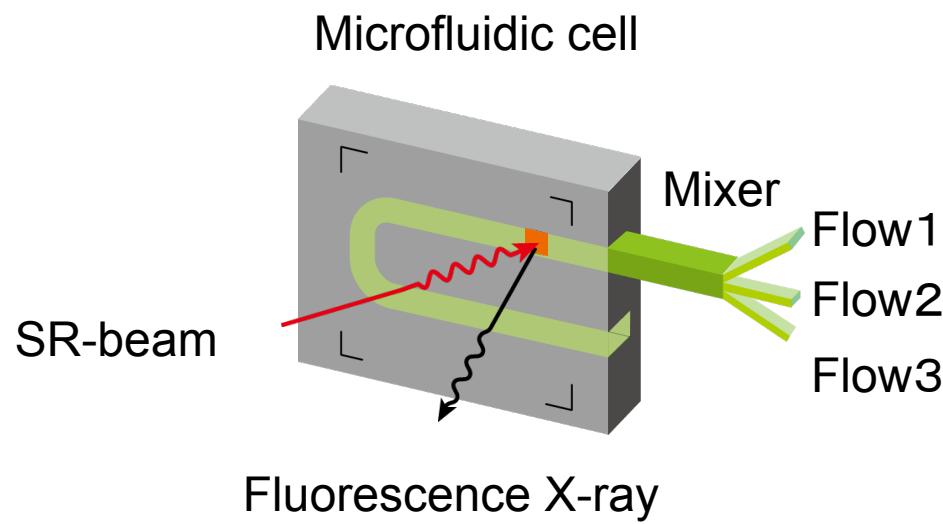
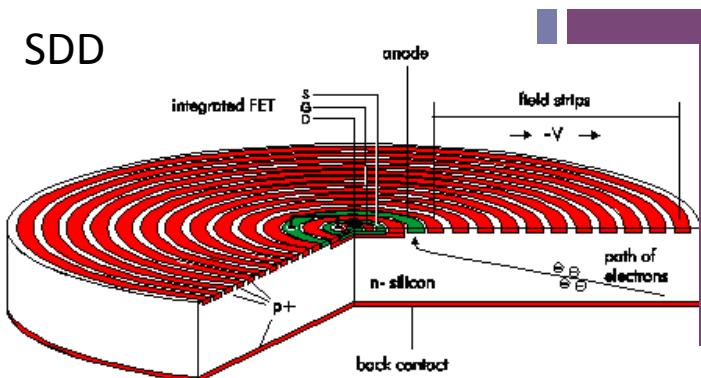
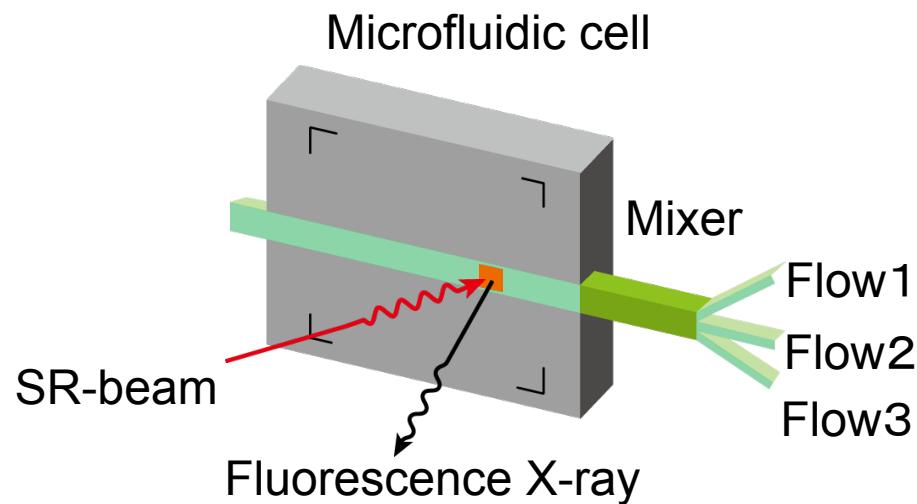
Oyanagi et al., J. of Luminescence 119, 361 (2006).

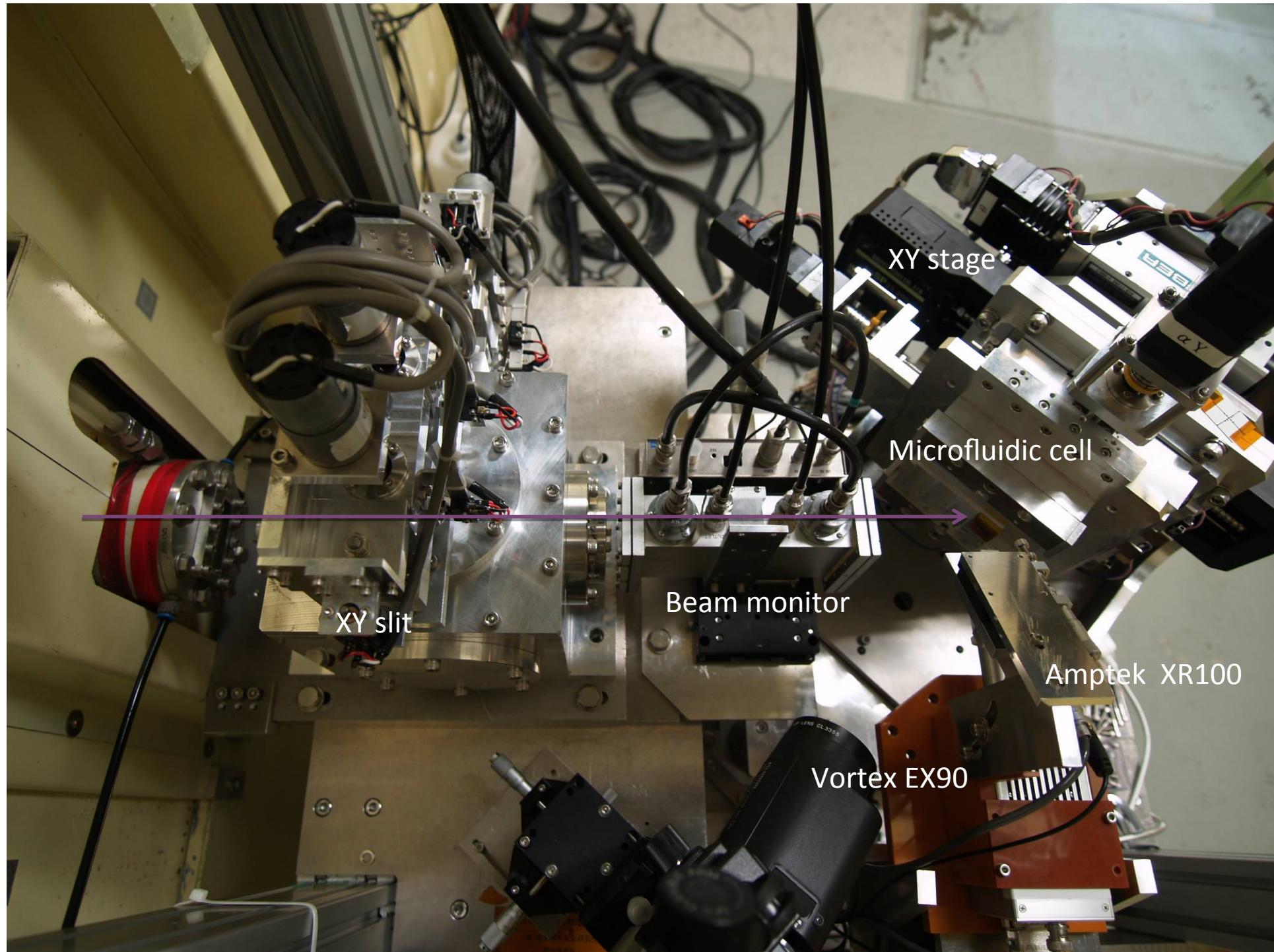


Vacuum-tight ion chambers and a fast SSD @ESRF



XAFS experiment using a microfluidic cell







Omitted topics

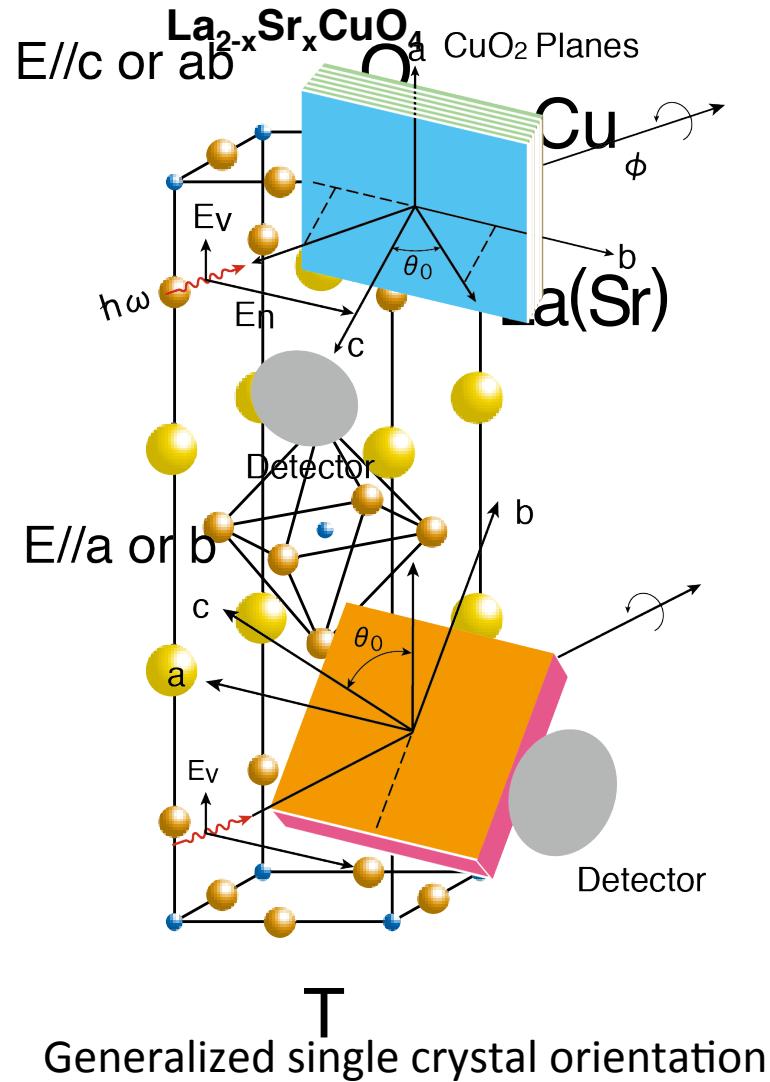
- Energy dispersive EXAFS
- Quick scan
- Pump & probe



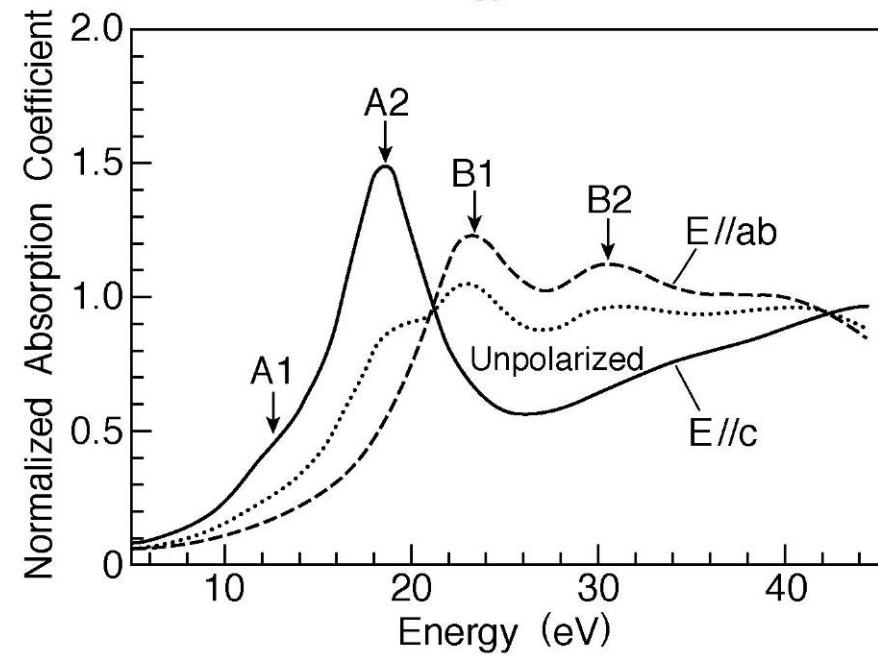
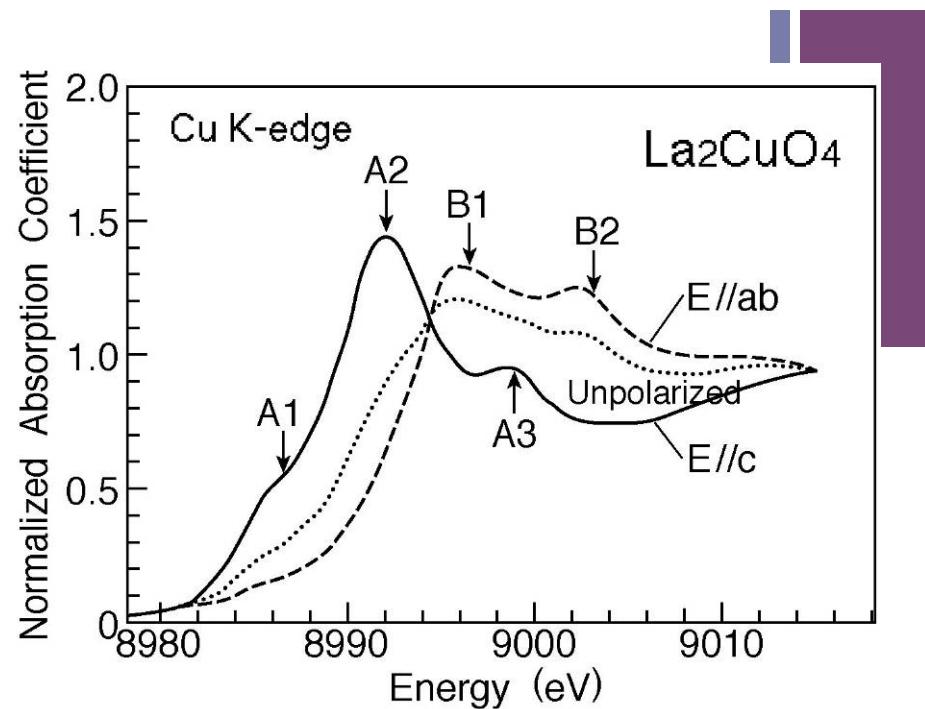
Measurement modes geometry

Transmission and fluorescence

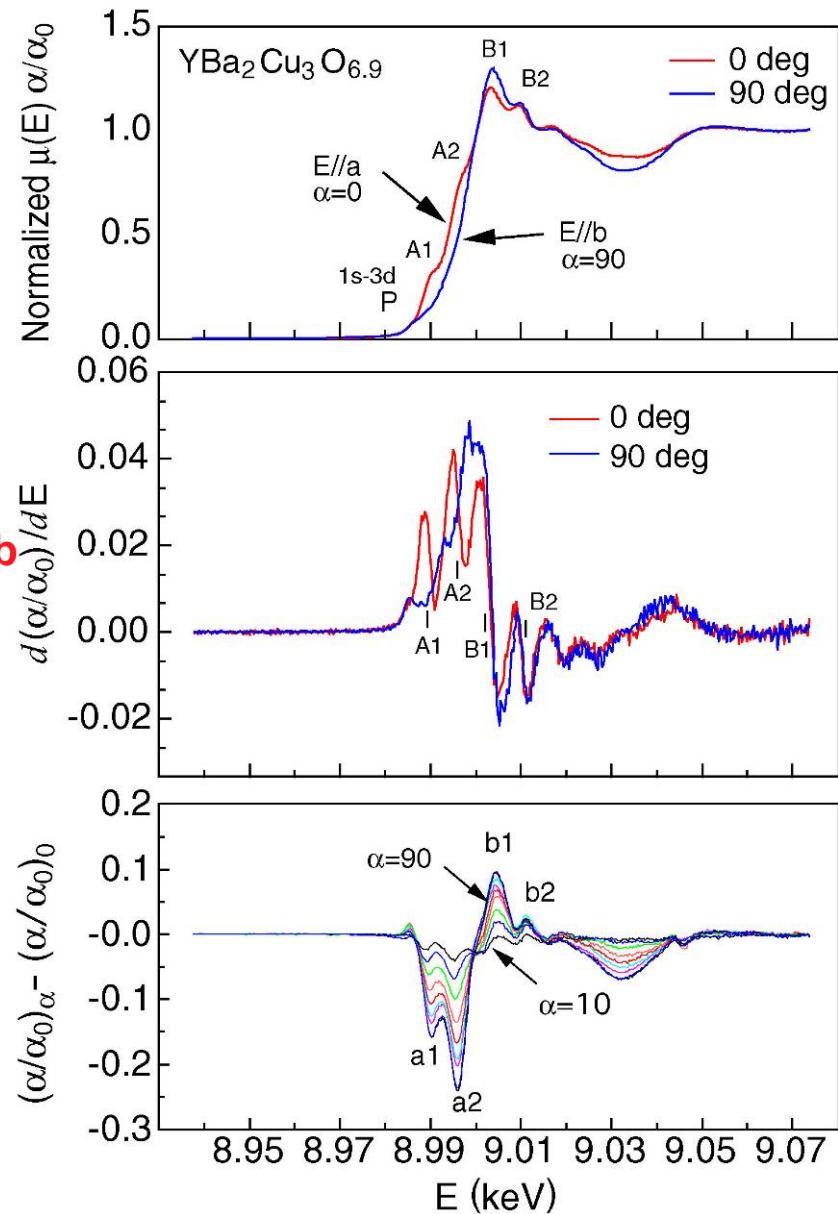
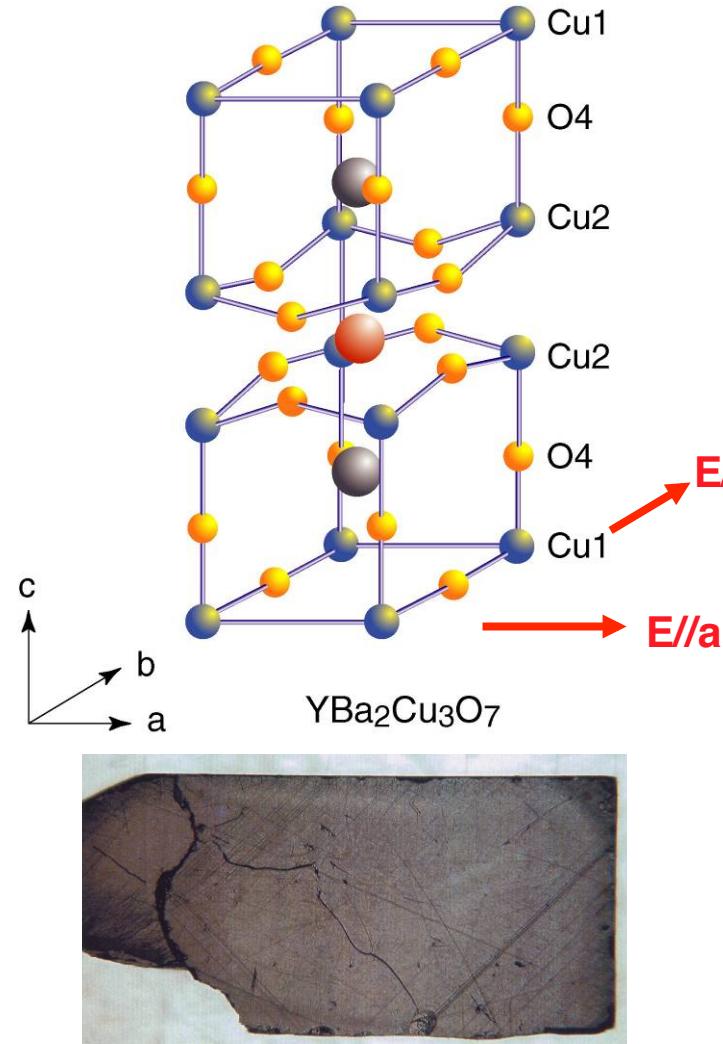
+ Geometries



Generalized single crystal orientation

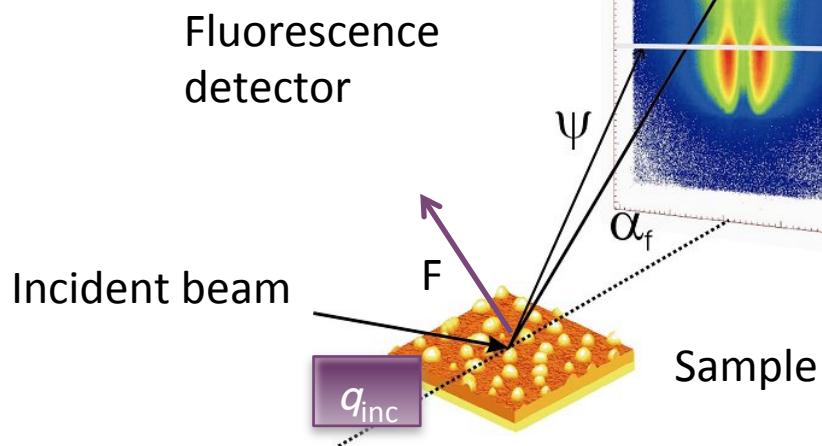


+ In-plane anisotropy



+ Grazing incidence geometry

Surface-sensitive geometry

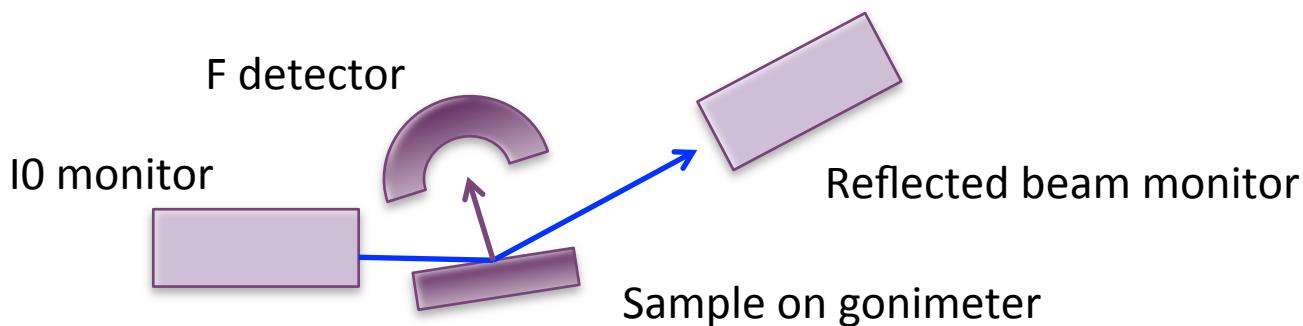


Surface scattered x-rays

Sensitivity ≈ 0.1 ML

In a total reflection regime, $q_{\text{inc}} < q_c$

Selective excitation of surface with background reduction is possible
Increasing surface sensitivity to 0.1 monolayer (ML) level





XSW (X-ray Standing Wave) set up Zegenhagen & Oyanagi @BL13/PF

Electrochemistry cell (GaAs substrate)

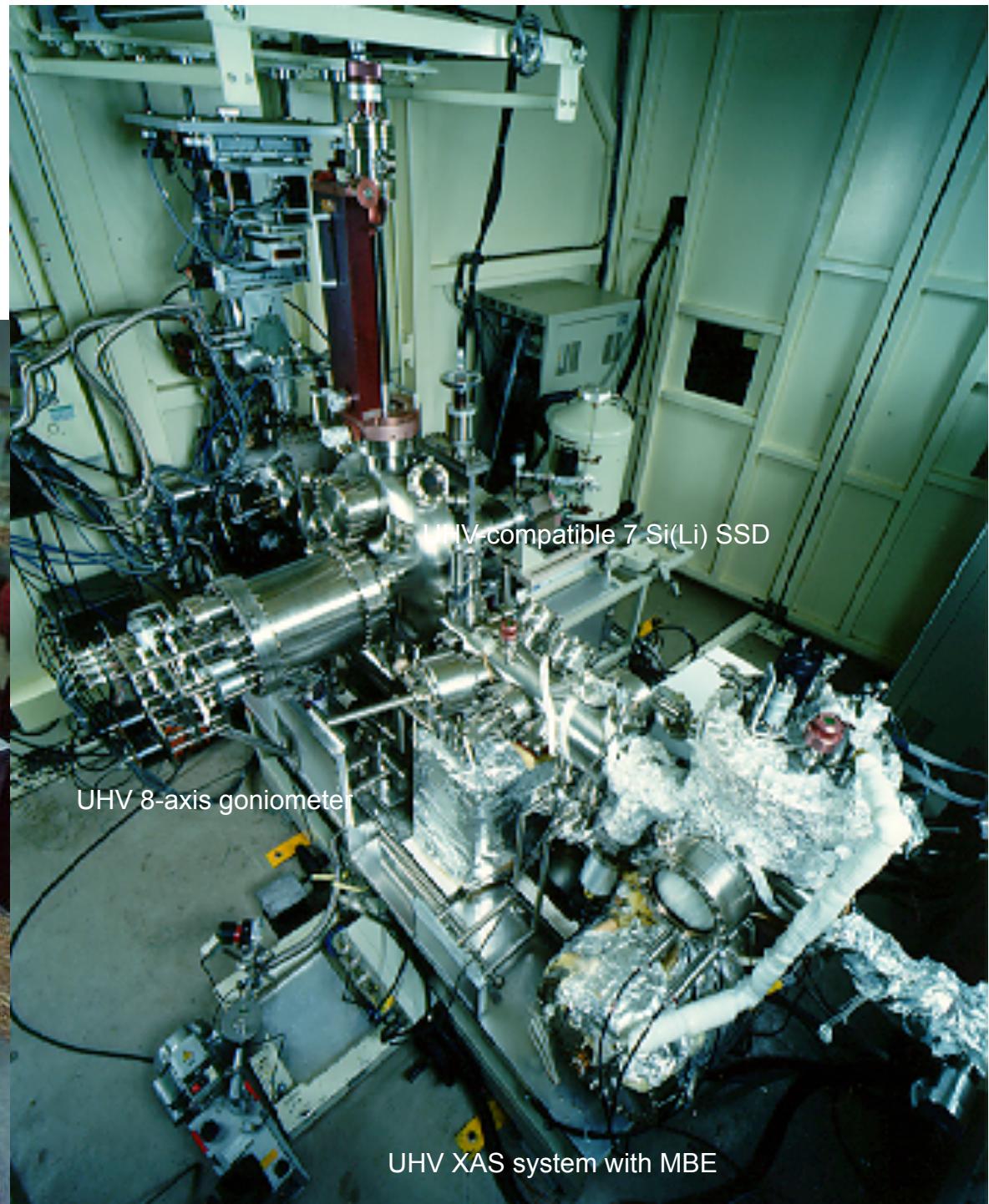


i₀ monitor (l=140 mm, N₂ gas)

ii (reflected beam)monitor
(l=280 mm, N₂ or N₂+Ar gas)

+ UHV fluorescence experiment

Rev. Sci. Instrum. 66,
5477 (1995)



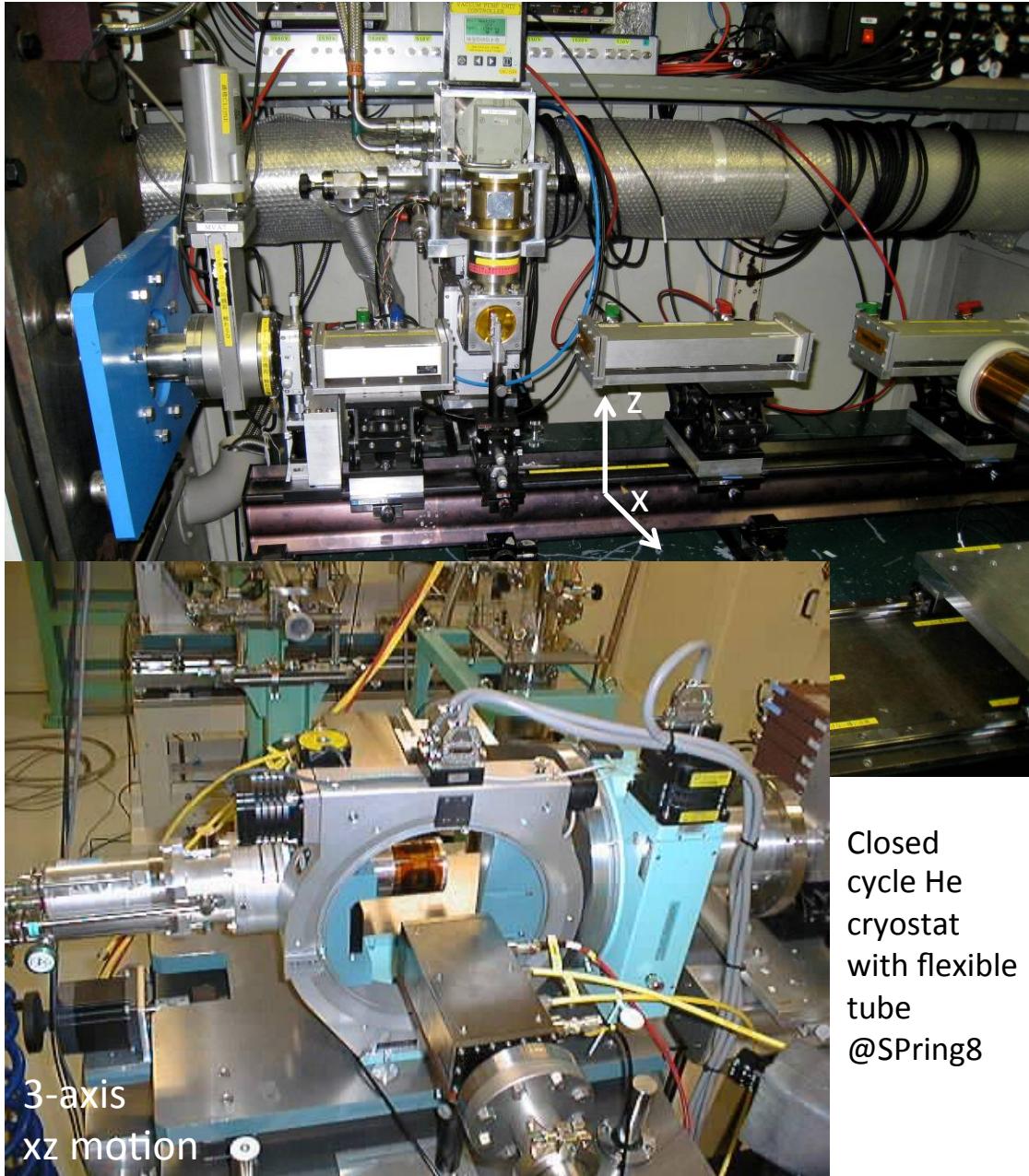
+

Sample preparation methods

Some hints for better experiments

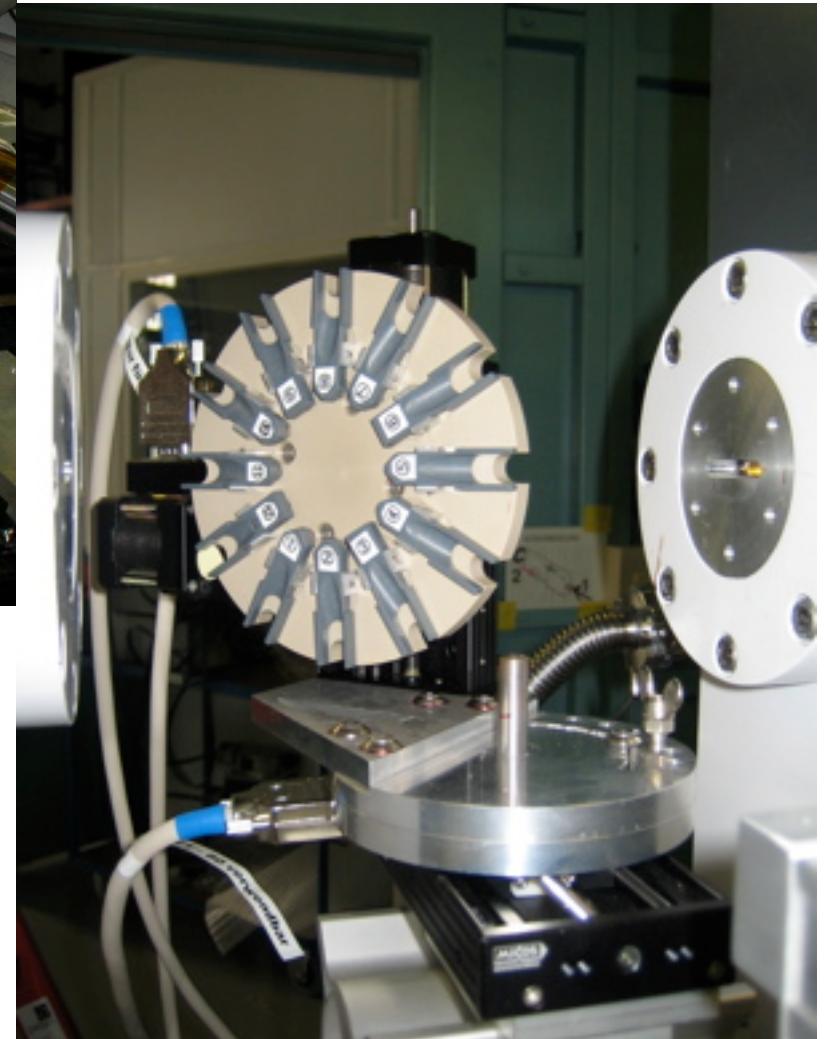
+ Cryostat

Closed cycle He cryostat @KEK



Closed cycle He cryostat @KEK

Multi sample holder
@ANKA



Closed
cycle He
cryostat
with flexible
tube
@SPring8

+ Sample preparation

General

Detailed description of sample preparation is available at xafs.org by the following researchers

Grant Bunker

Matt Newville
Rob Scarroo
Scott Calvin

URLs for each description available at xafs.org

Transmission experiment (Powder specimen)

<http://www.xafs.org/Experiment/DoublyContainedSamples>

Homogeneity and right thickness/concentration

Fluorescence experiment (single crystal)

Orientation and surface roughness

Temperature dependence

Stress-free good thermal contact



XAFS.org



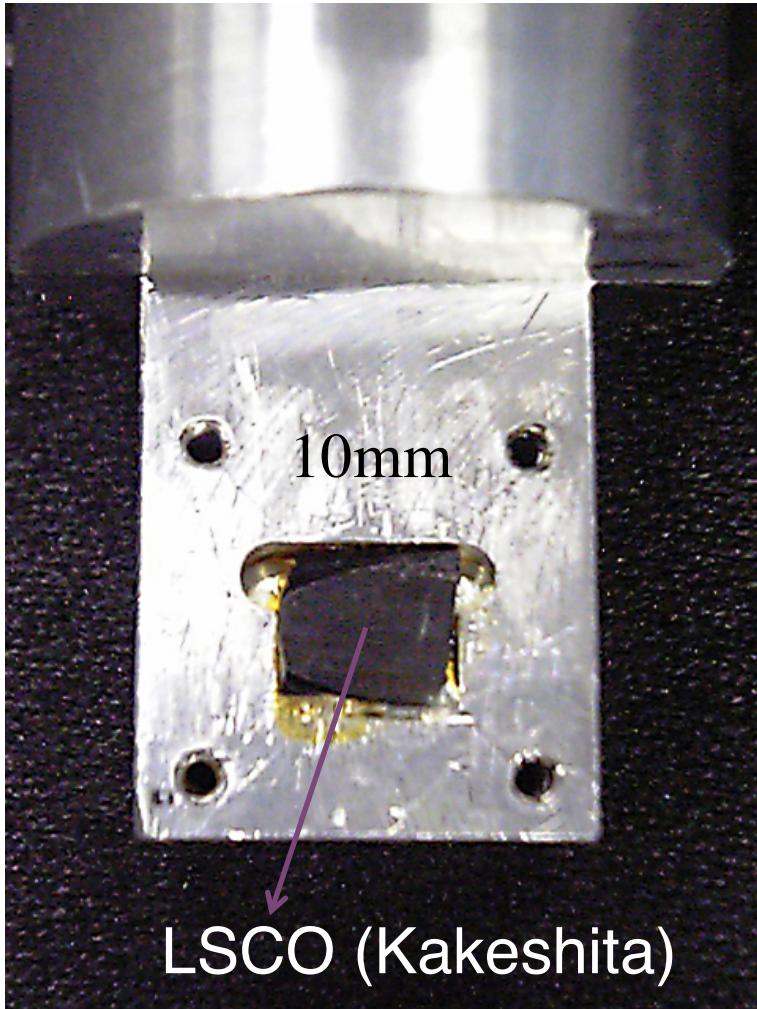
Pellet sample



Press

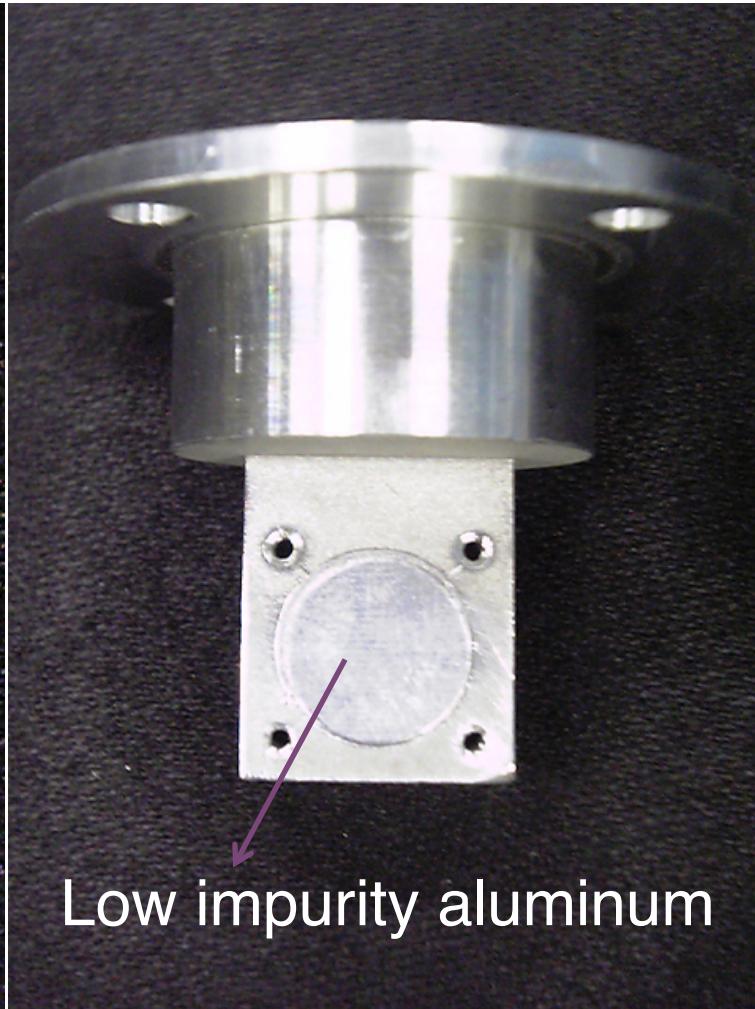
+ Sample mounting (bulk single crystals)

Large single crystal mounted on an aluminum base (left), smaller crystal mounted on impurity-free base (right)



LSCO on a standard type

2-4mm



1mm or less

+ Enjoy your experiment –Survival tips



- * S - Size Up the Situation
- * U - Use All Your Senses, Undue Haste Makes Waste
- * R - Remember Where You Are
- * V - Vanquish Fear and Panic
- * I - Improvise
- * V - Value Living
Anatoly Fronkel at NSLS beam line X16C.
- * A - Act Like the Natives
- * L - Live by Your Wits, But for Now, Learn Basic Skills

taken from the U.S. Army Survival Manual

